


<b>Search Notes</b>  	<b>Application/Control No.</b>  10527120	<b>Applicant(s)/Patent Under Reexamination</b>  TIEKE ET AL.
	<b>Examiner</b>  TAN X DINH	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner
369	275.1	5/05/08	T.D
	94	5/05/08	T.D
Updated above		11/19/08	T.D
369	275.3, 275.1, 94	6/12/09	T.D
428	64.1	6/12/09	T.D
430	320, 321, 270.1, 270.11, 270.13	6/12/09	T.D
Updated		11/20/09	T.D

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (see search history printout).	5/05/08	T.D
Updated	11/10/08	T.D
Updated	6/12/09	T.D
Updated	11/20/09	T.D

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
Interference Search History Printout		11/20/09	T.D

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